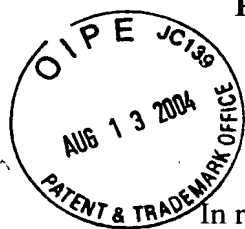


IFW



Patent

Customer No. 31561  
Docket No. 13114-US-PA  
Application No.: 10/709,719

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of

Applicant : Tang  
Application No. : 10/709,719  
Filed : 2004/5/25  
For : MULTI-GATE DRAM WITH DEEP-TRENCH CAPACITOR  
AND FABRICATION THEREOF  
Examiner :  
Art Unit : 2818

**INFORMATION DISCLOSURE STATEMENT**

ASSISTANT COMMISSIONER FOR PATENTS  
Arlington, VA22202

Enclosed is a PTO Form 1449 listing 2 reference(s), copy of which is attached. Applicant submits the reference(s) in compliance with his duty of disclosure pursuant to 37 CFR § 1.56 and 1.97. The Examiner is requested to make the citation(s) of official record.

This IDS is being submitted before the first Office Action. Thus, it is believed no fee is due.

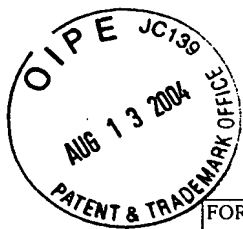
The submission of the reference(s) should not be interpreted as admitting them as prior art.

Respectfully Submitted,  
JIANQ CHYUN Intellectual Property Office

Date: August 11, 2004

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICATION	ATTY. DOCKET NO.: 13114-US-PA	APPLICATION NO.: 10/709,719
	APPLICANT: Tang	
	FILING DATE: May 25, 2004	GROUP 2818

**U.S. PATENT DOUCTIONS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FIILNG DATE (IF APPROPRIATE)

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	FIILNG DATE (IF APPROPRIATE)

EXAMINER INITIAL	<b>OTHER DOCUMENTS</b> (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	Radens et al., " A 0.135 $\mu\text{m}^2$ 6F <sup>2</sup> Trench-Sidewall Vertical Device Cell for 4Gb/16Gb DRAM", 2000 Symposium on VLSI Technology Digest of Technical Papers, pp. 80-81.
	Mandelman et al., " Challenges and future directions for the scaling of dynamic random-access memory (DRAM), in IBM J. RES. & DEV. Vol. 46 No. 2/3 March/ May 2002, pp. 187-212.

EXAMINER	DATE CONSIDERED
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**EXAMINER:** INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEST COMMUNICATION TO APPLICANT.